

Notice of References Cited	Application/Control No. 10/774,943		Applicant(s)/Patent Under Reexamination DEWAELE, PIET	
	Examiner MANAV SETH		Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,872,870	02-1999	Michael, David	382/291
*	B	US-5,343,390	08-1994	Doi et al.	382/132
*	C	US-6,011,862	01-2000	Doi et al.	382/132
*	D	US-6,263,097	07-2001	Dewaele, Piet	382/132
*	E	US-6,658,145	12-2003	Silver et al.	382/149
*	F	US-3,292,148	12-1966	GIULIANO VINCENT E et al.	382/212
*	G	US-5,317,652	05-1994	Chatterjee, Chanchal	382/304
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP1256907A9	11-2002			
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Y. Kawata et al. ("Curvature based characterization of shape and internal intensity structure for classification of pulmonary nodules using thin-section CT images", SPIE Conference on Image Processing, Vol. 3661, pages 541-552, San Diego, February 1999).
	V	P. Dewaele, M. Ibison, and P. Vuylsteke ("A Trainable rule-based network for irradiation field recognition in AGFA's ADC system," Proc. of SPIE - Vol. 2708, Medical Imaging: Physics of Medical Imaging, R. Van Metter, J. Beutel, Editors, April 1996, pp. 72-84).
	W	R. Desai and H.D. Cheng ("Pattern recognition by local radial moments," Pattern Recognition, Computer Vision & Image Processing, Proceedings of the 12th IAPR International Conference on vol. 2, no. pp.168-172, 9-13 Oct 1994)
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.